

T-Module G3VM-61MT/-101MT

Higher Accuracy Achieves extremely low leakage current of 1pA or less, which was difficult with traditional MOS relays, improves the measurement accuracy of equipment.

Maintains test performance comparable to reed relays.*

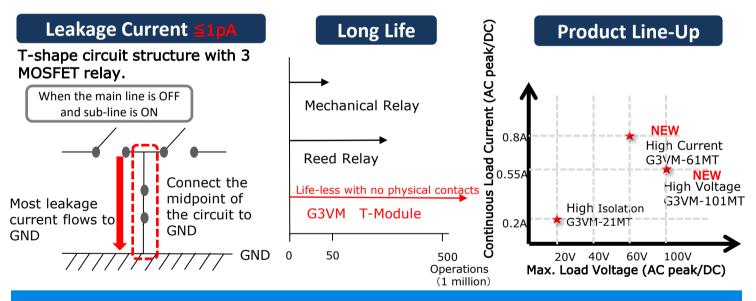
Longer Lifetime Reduces frequency of relay maintenance with makeup of semiconductors with no physical contacts.

Space saving

Contributes to both space saving and high integration with placing 3 relay circuits in one very small package. This enables having multiple functions and channels for equipment.

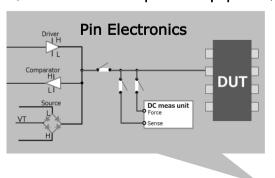
* According to a survey by OMRON Corporation in May 2021

Technical Overview



Application

ATE (Semiconductor inspection equipment)



Can be used in applications where it was difficult to replace from reed relays, such as equipment for high-precision measurements, due to dramatically improved leakage current.

